

<IGBT Modules>

CM100DY-24T

HIGH POWER SWITCHING USE INSULATED TYPE



dual switch (half-bridge)

- dual switch (half-bridge)
- Copper base plate (Nickel-plating)
- Tin-plating tab terminals
- •RoHS Directive compliant
- •UL Recognized under UL1557, File No. E323585

APPLICATION

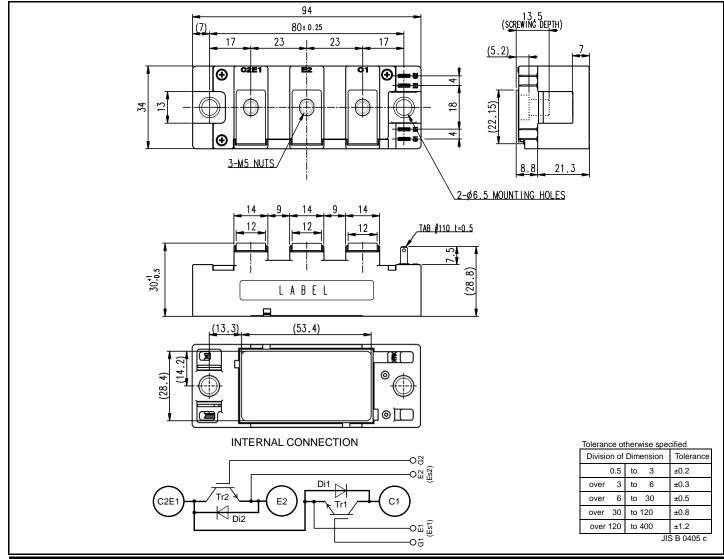
AC Motor Control, Motion/Servo Control, Power supply, etc.

OPTION (Below options are available.)

●PC-TIM (Phase Change Thermal Interface Material) pre-apply

OUTLINE DRAWING & INTERNAL CONNECTION

Dimension in mm



1

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INSULATED TYPE

MAXIMUM RATINGS (T_{vj} =25 °C, unless otherwise specified)

Symbol	Item	Conditions	Rating	Unit	
V _{CES}	Collector-emitter voltage	G-E short-circuited	1200	V	
V _{GES}	Gate-emitter voltage	C-E short-circuited	± 20	V	
Ic	Collector current	DC, T _C =125 °C (Note2, 4)	100	^	
I _{CRM}	Collector current	Pulse, Repetitive (Note3)	200	A	
P _{tot}	Total power dissipation	T _C =25 °C (Note2, 4)	1180	W	
I _E (Note1)	Facition account	DC (Note2)		^	
I _{ERM} (Note1)	Emitter current	Pulse, Repetitive (Note3)	200	Α	
V _{isol}	Isolation voltage	Terminals to base plate, RMS, f=60 Hz, AC 1 min	4000	V	
T _{vjmax}	Maximum junction temperature	Instantaneous event (overload)	175	°C	
T _{Cmax}	Maximum case temperature	(Note4)	125		
T _{vjop}	Operating junction temperature	Continuous operation (under switching)	-40 ~ +150	°C	
T _{stg}	Storage temperature	-	-40 ~ +125		

ELECTRICAL CHARACTERISTICS (Tvj=25 °C, unless otherwise specified)

Symbol	Item Conditions			Limits			Unit	
Symbol	Item	Conditions		Min.	Тур.	Max.	Unit	
I _{CES}	Collector-emitter cut-off current	V _{CE} =V _{CES} , G-E short-circuited	-	-	1.0	mA		
I _{GES}	Gate-emitter leakage current	V _{GE} =V _{GES} , C-E short-circuited	-	-	0.5	μΑ		
V _{GE(th)}	Gate-emitter threshold voltage	I _C =10 mA, V _{CE} =10 V	5.4	6.0	6.6	V		
		I _C =100 A, V _{GE} =15 V,	T _{vj} =25 °C	-	1.65	1.95	V	
V _{CEsat}		Refer to the figure of test circuit	T _{vj} =125 °C	-	1.85	-		
(Terminal)		(Note5)	T _{vj} =150 °C	-	1.90	-		
	Collector-emitter saturation voltage	I _C =100 A,	T _{vj} =25 °C	-	1.55	1.80		
V _{CEsat}		V _{GE} =15 V,	T _{vj} =125 °C	-	1.75	-	V	
(Chip)		(Note5)	T _{vj} =150 °C	-	1.80	-	1	
Cies	Input capacitance			_	-	22.8	nF	
Coes	Output capacitance	V _{CE} =10 V, G-E short-circuited		-	-	0.8		
Cres	Reverse transfer capacitance		-	-	0.3			
Q _G	Gate charge	V _{CC} =600 V, I _C =100 A, V _{GE} =15 V	-	0.7	-	μC		
t _{d(on)}	Turn-on delay time	Vcc=600 V, Ic=100 A, V _{GE} =±15 V,		-	-	300	- ns	
tr	Rise time			-	-	150		
t _{d(off)}	Turn-off delay time			-	-	500		
t _f	Fall time	R_G =3.9 Ω , Inductive load	-	-	300			
) (Nata 4)	En Westerland	I _E =100 A, G-E short-circuited,	T _{vj} =25 °C	-	1.70	2.10		
V _{EC} (Note.1)		Refer to the figure of test circuit	T _{vj} =125 °C	-	1.85	-	- V	
(Terminal)		(Note5)	T _{vj} =150 °C	-	1.85	-		
(Note 4)	- Emitter-collector voltage	I _E =100 A,	T _{vj} =25 °C	-	1.65	2.00		
V _{EC} (Note.1)		G-E short-circuited,	T _{vj} =125 °C	=	1.65	-	V	
(Chip)		(Note5)	T _{vj} =150 °C	=	1.65	-		
t _{rr} (Note1)	Reverse recovery time	V _{CC} =600 V, I _E =100 A, V _{GE} =±15 V,		-	-	400	ns	
Q _{rr} (Note1)	Reverse recovery charge	$R_G=3.9 \Omega$, Inductive load		-	10	-	μC	
Eon	Turn-on switching energy per pulse	V_{CC} =600 V, I_{C} = I_{E} =100 A, V_{GE} =±15 V, R_{G} =3.9 Ω , T_{vj} =150 °C,		-	5.5	-	1	
E _{off}	Turn-off switching energy per pulse			-	11.2	-	mJ	
E _{rr} (Note1)	Reverse recovery energy per pulse	Inductive load	-	7.9	-	mJ		
R _{CC'+EE'}	Internal lead resistance	Main terminals-chip, per switch, T _C =25 °	-	0.2	-	mΩ		
r _g	Internal gate resistance	Per switch	-	0	-	Ω		

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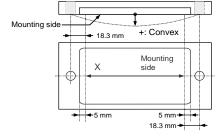
THERMAL RESISTANCE CHARACTERISTICS

Symbol	Item	Conditions		Limits			Unit
				Min.	Тур.	Max.	Offic
$R_{th(j-c)Q}$	Thermal resistance	Junction to case, per Inverter IGBT (Note4)		-	-	127	K/kW
$R_{th(j-c)D}$	Thermal resistance	Junction to case, per Inverter FWD (Note4)		=	-	228	
R _{th(c-s)}	Contact thermal resistance	Case to heat sink,	Thermal grease applied (Note4, 6)	1	36.6	1	K/kW
		per 1 module,	PC-TIM applied (Note4, 7)	=	9.7	=	IVAVV

MECHANICAL CHARACTERISTICS

Symbol	Itom	Conditions		Limits			Unit
	Item			Min.	Тур.	Max.	Onit
M _t	Mounting torque	Main terminals	M 5 screw	2.5	3.0	3.5	N∙m
Ms	Mounting torque	Mounting to heat sink	M 6 screw	3.5	4.0	4.5	N∙m
ds	Creepage distance	Terminal to terminal		18.4	=	-	
		Terminal to base plate		21.1	-	-	mm
da	Clearance	Terminal to terminal	terminal		-	-	mm
	Clearance	Terminal to base plate		16.7	-	-	mm
ec	Flatness of base plate	On the centerline (Note8)		±0	=	+200	μm
m	mass	-		-	120	-	g

- *: This product is compliant with the Restriction of the Use of Certain Hazardous Substances in Electrical and Electronic Equipment (RoHS) directive 2011/65/EU.
- Note1. Represent ratings and characteristics of the anti-parallel, emitter-collector free-wheeling diode (FWD).
 - 2. Junction temperature $(T_{\nu j})$ should not increase beyond $T_{\nu j\,m\,a\,x}$ rating.
 - 3. Pulse width and repetition rate should be such that the device junction temperature (T_{vj}) dose not exceed T_{vjmax} rating.
 - 4. Case temperature (T_C) and heat sink temperature (T_S) are defined on the each surface (mounting side) of base plate and heat sink just under the chips. Refer to the figure of chip location.
 - 5. Pulse width and repetition rate should be such as to cause negligible temperature rise. Refer to the figure of test circuit.
 - 6. Typical value is measured by using thermally conductive grease of λ =0.9 W/(m·K)/D_(C-S)=50 μ m.
 - 7. Typical value is measured by using PC-TIM of $\lambda{=}3.4~\text{W/(m\cdot K)/D_{(C\text{-}S)}}{=}50~\mu\text{m}.$
 - 8. The base plate (mounting side) flatness measurement point is as follows of the following figure.



Publication Date : February 2017 CMH-11286 Ver.1.0

HIGH POWER SWITCHING USE

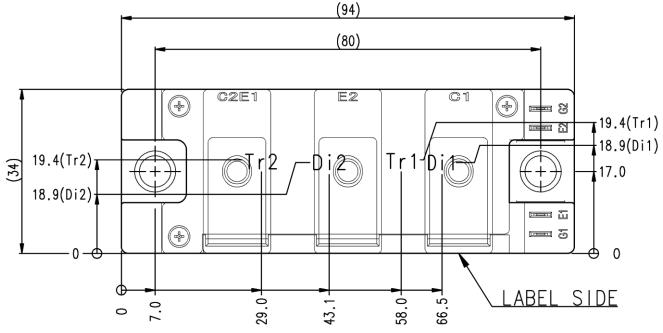
INSULATED TYPE

RECOMMENDED OPERATING CONDITIONS

Symbol	Item	Conditions	Limits			Unit
	item	Conditions	Min.	Тур.	Max.	Unit
V _{cc}	(DC) Supply voltage	Applied across C1-E2 terminals	-	600	850	V
V_{GEon}	Gate (-emitter drive) voltage	Applied across G1-Es1/G2-Es2 terminals	13.5	15.0	16.5	V
R _G	External gate resistance	Per switch	3.9	-	91	Ω

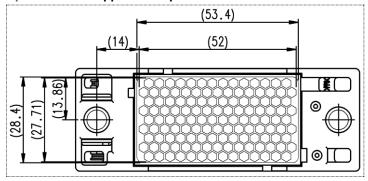
CHIP LOCATION (Top view)

Dimension in mm, tolerance: ±1 mm

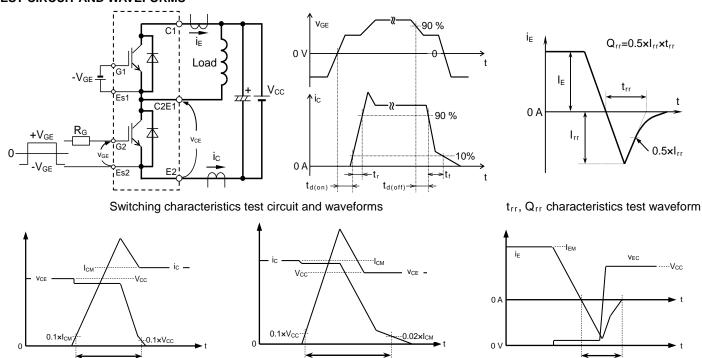


Tr1/Tr2: IGBT, Di1/Di2: FWD

Option: PC-TIM applied baseplate outline



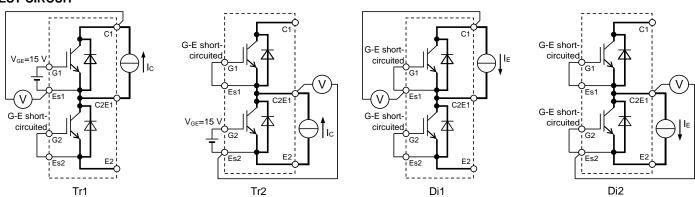
TEST CIRCUIT AND WAVEFORMS



IGBT Turn-off switching energy Turn-on / Turn-off switching energy and Reverse recovery energy test waveforms (Integral time instruction drawing)

TEST CIRCUIT

IGBT Turn-on switching energy



V_{CEsat} characteristics test circuit

V_{EC} characteristics test circuit

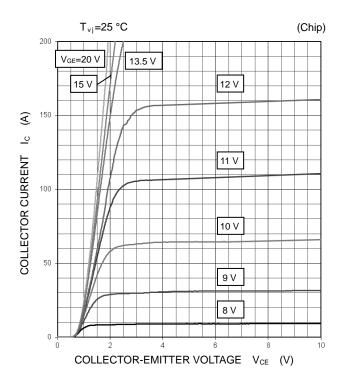
FWD Reverse recovery energy

HIGH POWER SWITCHING USE

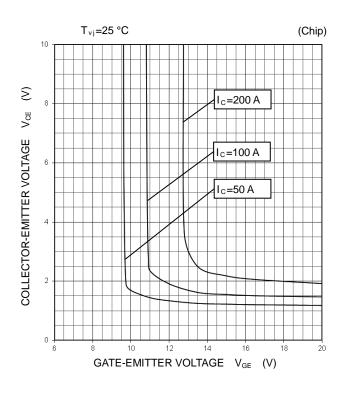
INSULATED TYPE

PERFORMANCE CURVES

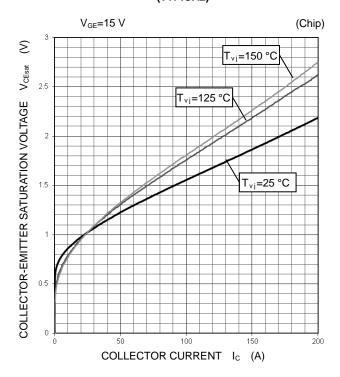
OUTPUT CHARACTERISTICS (TYPICAL)



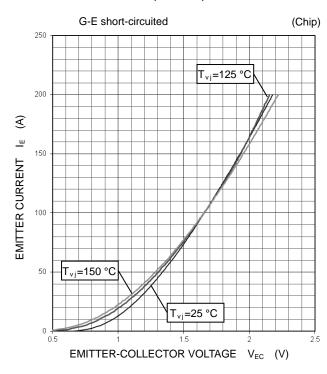
COLLECTOR-EMITTER VOLTAGE CHARACTERISTICS (TYPICAL)



COLLECTOR-EMITTER SATURATION VOLTAGE CHARACTERISTICS (TYPICAL)



FREE WHEELING DIODE FORWARD CHARACTERISTICS (TYPICAL)

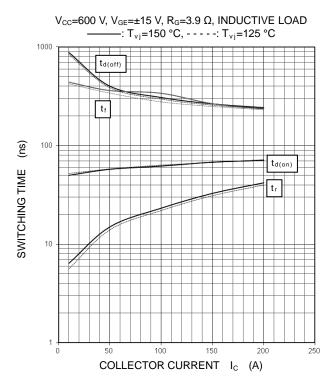


HIGH POWER SWITCHING USE

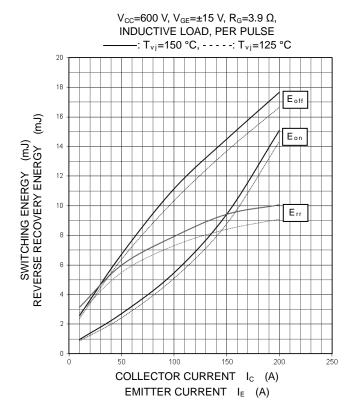
INSULATED TYPE

PERFORMANCE CURVES

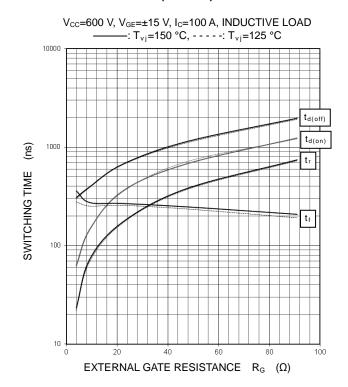
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



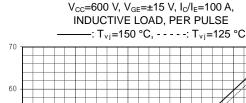
HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)

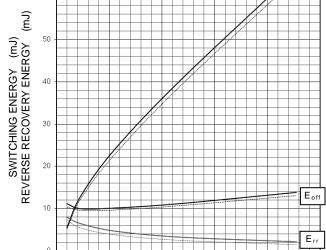


HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)



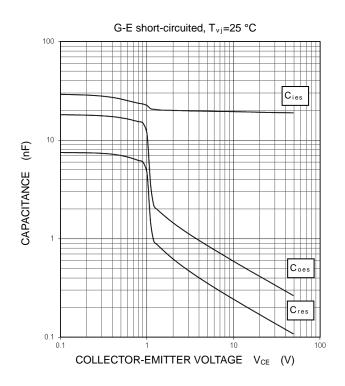


EXTERNAL GATE RESISTANCE R_G (Ω)

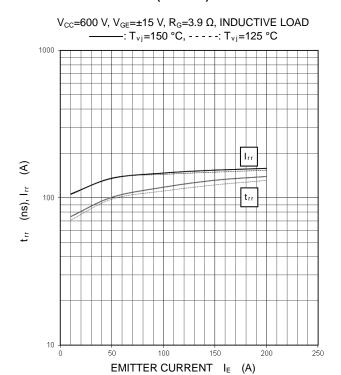
100

PERFORMANCE CURVES

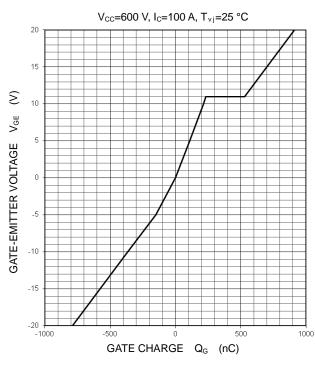
CAPACITANCE CHARACTERISTICS (TYPICAL)



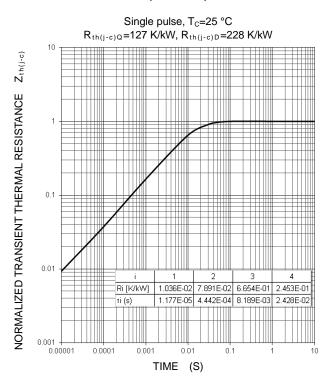
FREE WHEELING DIODE REVERSE RECOVERY CHARACTERISTICS (TYPICAL)



GATE CHARGE CHARACTERISTICS (TYPICAL)



TRANSIENT THERMAL IMPEDANCE CHARACTERISTICS (MAXIMUM)

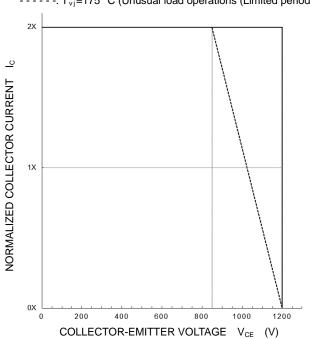


Note: The characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

PERFORMANCE CURVES

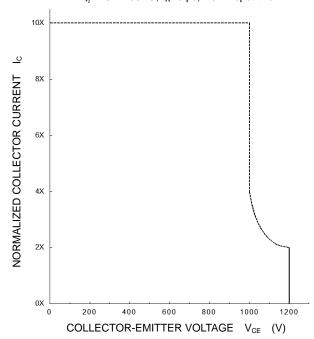
TURN-OFF SWITCHING SAFE OPERATING AREA (REVERSE BIAS SAFE OPERATING AREA) (MAXIMUM)

 V_{CC} ≤850 V, V_{GE} =±15 V, R_{G} =3.9~91 Ω ,
——: T_{vj} =25~150 °C (Normal load operations (Continuous)
-----: T_{vj} =175 °C (Unusual load operations (Limited period)



SHORT-CIRCUIT SAFE OPERATING AREA (MAXIMUM)

 $V_{\text{CC}} \leq 800 \text{ V}, V_{\text{GE}} = \pm 15 \text{ V}, R_{\text{G}} = 3.9 \sim 91 \Omega,$ $T_{\text{vi}} = 25 \sim 150 \text{ °C}, t_{\text{W}} \leq 8 \mu\text{s}, \text{Non-Repetitive}$



HIGH POWER SWITCHING USE INSULATED TYPE

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Publication Date : February 2017 CMH-11286 Ver.1.0